

<b>Notice of References Cited</b>		Application/Control No. 10/622,144	Applicant(s)/Patent Under Reexamination WIEDEMANN ET AL.	
		Examiner DAVID P. RASHID	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,640,468	06-1997	Hsu, Shin-yi	382/190
*	B US-6,618,490	09-2003	Cham et al.	382/103
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Statistical Framework for Long-Range Feature Matching in Uncalibrated Image Mosaicing, Cham et al., Computer Vision and Pattern Recognition, 1998 pp. 1-6
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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